# DATA SHEET 74F620 Octal bus transceiver, inverting (3tate) 74F623 Octal bus transceiver, non-inverting (3tate)

INTEGRATED CIRCUITS

Product specification

IC15 Data Handbook







1989 Apr 06

# 74F620/74F623

74F620 Octal Bus Transceiver, Inverting (3-State) 74F623 Octal Bus Transceiver, Non-Inverting (3-State)

### FEATURES

- High-impedance NPN base inputs for reduced loading (70μA in High and Low states)
- Ideal for applications which require high output drive and minimal bus loading
- Octal bidirectional bus interface
- 3-State buffer outputs sink 64mA and source 15mA
- 74F620, inverting
- 74F623, non-inverting

# DESCRIPTION

The 74F620 is an octal transceiver featuring inverting 3-State bus-compatible outputs in both send and receive directions. The outputs are capable of sinking 64mA and sourcing up to 15mA, providing very good capacitive drive characteristics. The 74F623 is a non-inverting version of the 74F620.

These octal bus transceivers are designed for asynchronous two-way communication between data buses. The control function implementation allows for maximum flexibility in timing.

These devices allow data transmission from the A bus to the B bus or from the B bus to the A bus depending upon the logic levels at the

# INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

Enable inputs (OEBA and OEAB). The Enable inputs can be used to disable the device so that the buses are effectively isolated.

The dual-enable configuration gives the 74F620 and 74F623 the capability to store data by the simultaneous enabling of OEBA and OEAB. Each output reinforces its input in this transceiver configuration. Thus, when both control inputs are enabled and all other data sources to the two sets of the bus lines are at high impedance, both sets of bus lines (16 in all) will remain in their last states.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F620	3.5ns	80mA
74F623	4.5ns	105mA

# ORDERING INFORMATION

DESCRIPTION	$\begin{array}{l} \text{COMMERCIAL RANGE} \\ \text{V}_{CC} = 5\text{V} \pm 10\%, \\ \text{T}_{amb} = 0^{\circ}\text{C to } + 70^{\circ}\text{C} \end{array}$	PKG DWG #	
20-pin plastic DIP	N74F620N, N74623N	SOT146-1	
20-pin plastic SOL	N74F620D, N74623D	SOT163-1	

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0 - A7, B0 - B7	Data inputs	3.5/1.16	70μΑ/70μΑ
OEBA, OEAB	Output Enable inputs	1.0/0.033	20μΑ/20μΑ
A0 - A7	Data outputs	150/40	3mA/24mA
B0 - B7	Data outputs	750/106.7	15mA/64mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

# **PIN CONFIGURATION – 74F620**

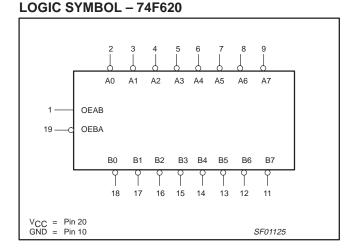
OEAB 1		
	20	VCC
A0 2	19	OEBA
A1 3	18	В0
A2 4	17	B1
A3 5	16	B2
A4 6	15	B3
A5 7	14	B4
A6 8	13	B5
A7 9	12	B6
GND 10	11	B7
	SF01	124

# **PIN CONFIGURATION – 74F623**

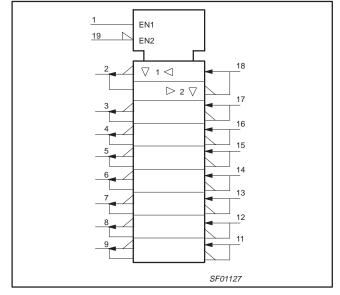
OEAB 1		20 VCC
A0 2	-	19 OEBA
A1 3	-	18 B0
A2 4	-	17 B1
A3 5	-	16 B2
A4 6	-	15 B3
A5 7	-	14 B4
A6 8	-	13 B5
A7 9	-	12 B6
GND 10	-	11 B7
I		
	Si	F01124

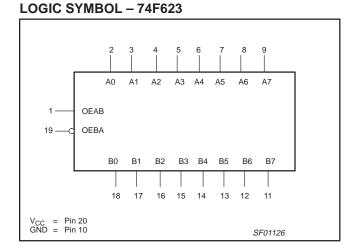
# Product specification

74F620/74F623

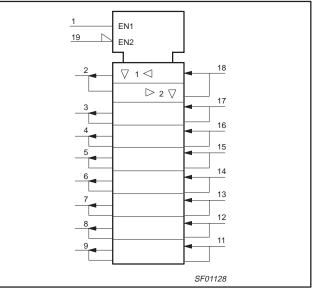


# IEC/IEEE SYMBOL (IEEE/IEC) – 74F620





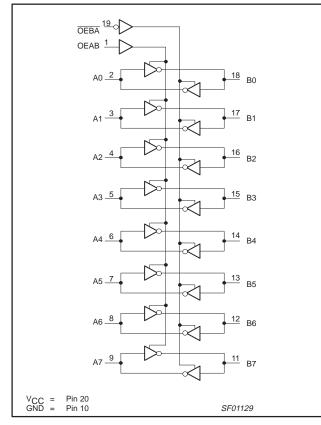
# IEC/IEEE SYMBOL (IEEE/IEC) - 74F623



# 74F620/74F623

Product specification

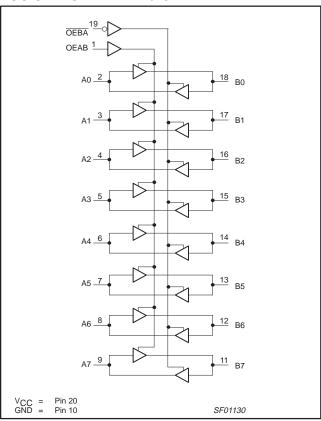
### LOGIC DIAGRAM - 74F620



### **FUNCTION TABLE**

INPUTS		OPERATING MODES				
OEBA	OEAB	74F620	74F623			
L	L	$\overline{B}$ data to A bus	B data to A bus			
Н	Н	$\overline{A}$ data to B bus	A data to B bus			
Н	L	Z	Z			
	н	$\overline{B}$ data to A bus	B data to A bus			
		$\overline{A}$ data to B bus	A data to B bus			

H=High voltage levelL=Low voltage levelX=Don't careZ=High impedance "off" state



# LOGIC DIAGRAM - 74F623

# 74F620/74F623

### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage	-0.5 to +7.0	V	
V <sub>IN</sub>	Input voltage	-0.5 to +7.0	V	
I <sub>IN</sub>	Input current	-30 to +5	mA	
V <sub>OUT</sub>	Voltage applied to output in High output state	–0.5 to +V <sub>CC</sub>	V	
	Current applied to output in Low output state	A0–A7	48	mA
lout	Current applied to output in Low output state	B0–B7	128	mA
T <sub>amb</sub>	Operating free-air temperature range		0 to +70	°C
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C

# **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARA					
STMBOL		MIN	NOM	MAX	UNIT	
V <sub>CC</sub>	Supply voltage		4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage		2.0			V
V <sub>IL</sub>	Low-level input voltage				0.8	V
I <sub>IK</sub>	Input clamp current				-18	mA
		A0–A7			-3	mA
ЮН		B0–B7			-15	mA
		A0–A7			24	mA
I <sub>OL</sub>	Low-level output current B0–B7				64	mA
T <sub>amb</sub>	Operating free-air temperature range	9	0		70	°C

# 74F620/74F623

# **DC ELECTRICAL CHARACTERISTICS**

(Over recommended operating free-air temperature range unless otherwise noted.)

						LIMITS				
SYMBOL	PARA	PARAMETER			TEST CONDITIONS <sup>NO TAG</sup>			TYP NO TAG	MAX	UNIT
			A0–A7		1 2m4	±10%V <sub>CC</sub>	2.4			V
V <sub>OH</sub>	High-level output v	oltago	B0–B7	$V_{CC} = MIN,$ $V_{IL} = MAX,$	I <sub>OH</sub> = -3mA	±5%V <sub>CC</sub>	2.7	3.3		V
VОН		onage	B0–B7	$V_{IH} = MIN$	I <sub>OH</sub> = -15mA	$\pm 10\% V_{CC}$	2.0			V
			00 07			±5%V <sub>CC</sub>	2.0			V
			A0–A7		I <sub>OL</sub> = 24mA	±10%V <sub>CC</sub>		0.35	0.50	V
V <sub>OL</sub>	Low-level output vo	oltage		$V_{CC} = MIN,$ $V_{IL} = MAX,$	10L - 2 mil (	±5%V <sub>CC</sub>		0.35	0.50	V
VOL		hago	B0–B7	$V_{IH} = MIN,$	I <sub>OL</sub> = 48mA	$\pm 10\% V_{CC}$		0.38	0.55	V
			00 01		$I_{OL} = 64mA$	$\pm 5\% V_{CC}$		0.42	0.55	V
V <sub>IK</sub>	Input clamp voltage	e		$V_{CC} = MIN, I_I$	= I <sub>IK</sub>			-0.73	-1.2	V
I <sub>I</sub>		Input current at maximum OEAB		V <sub>CC</sub> = 0.0V, V	<sub>1</sub> = 7.0V				100	μA
-1	input voltage		others	V <sub>CC</sub> = 5.5V, V	i = 5.5V				1	mA
I <sub>IH</sub>	High-level input cu	rrent	OEBA, OEAB	V <sub>CC</sub> = MAX, \	$V_{CC} = MAX, V_I = 2.7V$				20	μA
IIL	Low-level input cur	rent	only	V <sub>CC</sub> = MAX, \	$V_{CC} = MAX, V_I = 0.5V$				-20	μA
I <sub>OZH</sub> +I <sub>IH</sub>	Off-state output cur High-level of voltage		A0–A7	V <sub>CC</sub> = MAX, \	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V				70	μA
I <sub>OZL</sub> +I <sub>IL</sub>	Off-state output cur Low-level of voltage		B0–B7	V <sub>CC</sub> = MAX, \	/ <sub>I</sub> = 0.5V				-70	μΑ
los	Short-circuit output	t cur-	A0–A7	V <sub>CC</sub> = MAX			-60		-150	mA
OS	rent <sup>NO TAG</sup>		B0–B7	VCC - 10177	-		-100		-225	mA
			ICCH		OEBA=OEAB A0-A7=GND	=4.5V;		70	92	mA
		74F620	I <sub>CCL</sub>	V <sub>CC</sub> = MAX	OEBA=OEAB=4.5V; A0–A7=4.5V			84	110	mA
	Supply current		I <sub>CCZ</sub>		OEAB=GND; OEBA=A0-A7=4.5V			84	110	mA
ICC	(total)		I <sub>CCH</sub>		OEBA=OEAB=4.5V; A0–A7=4.5V			110	140	mA
		74F623	I <sub>CCL</sub>	V <sub>CC</sub> = MAX	MAX OEBA=OEAB=4.5V; A0-A7=GND			110	140	mA
			I <sub>CCZ</sub>		OEAB=GND; OEBA=A0–A7=4.5V			99	130	mA

### NOTES:

<sup>1.</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. 2. All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25^{\circ}C$ . 3. Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS tests should be performed last.

# 74F620/74F623

# **AC ELECTRICAL CHARACTERISTICS – 74F620**

			LIMITS					
SYMBOL	PARAMETER	TEST CONDITION	V <sub>CC</sub> = +5V T <sub>amb</sub> = +25°C C <sub>L</sub> = 50pF, R <sub>L</sub> = 500Ω			V <sub>CC</sub> = +5 T <sub>amb</sub> = 0°C C <sub>L</sub> = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to Bn	Waveform 2	2.5 1.0	4.5 2.5	6.5 4.5	2.0 1.0	7.5 5.0	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Bn to An	Waveform 2	2.5 1.0	4.5 2.5	6.5 4.5	2.0 1.0	7.5 5.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable time to High or Low level, OEBA to An	Waveform 3 Waveform 4	3.0 4.0	7.5 7.5	10.5 10.5	2.5 3.5	11.5 11.5	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable time to High or Low level, OEBA to An	Waveform 3 Waveform 4	2.5 2.0	4.5 4.5	7.5 7.0	2.0 1.5	8.0 7.5	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable time to High or Low level, OEAB to Bn	Waveform 3 Waveform 4	4.5 4.5	7.5 7.5	10.5 10.0	4.0 4.0	11.5 11.0	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable time to High or Low level, OEAB to Bn	Waveform 3 Waveform 4	3.0 4.0	6.5 6.5	9.5 9.5	2.5 3.5	10.5 10.5	ns

# AC ELECTRICAL CHARACTERISTICS - 74F623

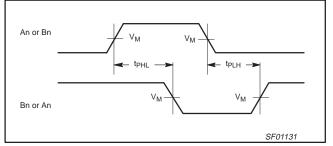
			LIMITS					
SYMBOL	PARAMETER	TEST CONDITION	$V_{CC} = +5V$ $T_{amb} = +25^{\circ}C$ $C_{L} = 50pF, R_{L} = 500\Omega$			V <sub>CC</sub> = +5 T <sub>amb</sub> = 0°C C <sub>L</sub> = 50pF,	UNIT	
			MIN	ТҮР	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to Bn	Waveform 1	2.0 3.0	4.0 5.0	5.5 7.0	2.0 2.5	6.5 7.5	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay Bn to An	Waveform 1	2.0 2.5	4.0 4.5	5.5 6.5	2.0 2.5	6.5 7.5	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable time to High or Low level, OEBA to An	Waveform 3 Waveform 4	5.0 5.0	8.5 7.5	10.5 9.5	5.0 5.0	12.0 10.0	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable time to High or Low level, OEBA to An	Waveform 3 Waveform 4	2.5 2.5	4.5 4.5	6.5 6.5	2.5 2.5	7.5 7.0	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable time to High or Low level, OEAB to Bn	Waveform 3 Waveform 4	5.0 4.5	8.0 7.0	10.0 9.0	5.0 4.5	11.5 9.5	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable time to High or Low level, OEAB to Bn	Waveform 3 Waveform 4	3.0 4.0	6.0 7.0	8.5 9.0	3.0 4.0	10.0 10.0	ns

### Product specification

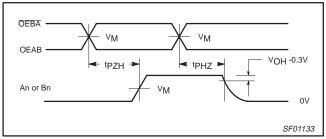
# 74F620/74F623

### AC WAVEFORMS

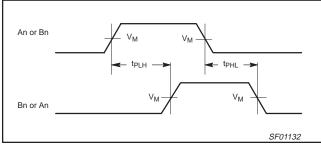
For all waveforms, V<sub>M</sub> = 1.5V.



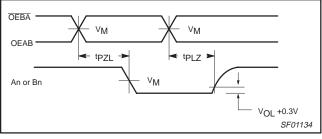
### Waveform 1. For Inverting Outputs



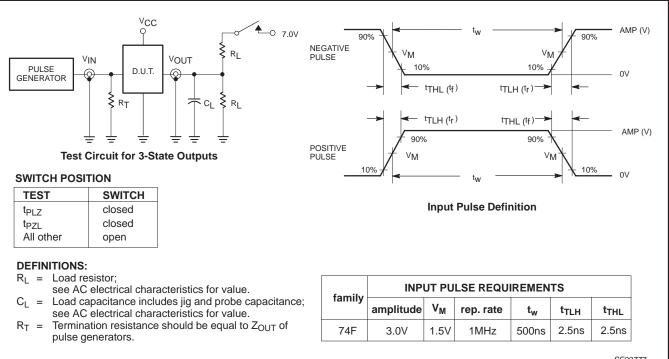
Waveform 3. 3-State Output Enable Time to High Level and **Output Disable Time from High Level** 



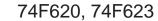
Waveform 2. For Non-Inverting Outputs



Waveform 4. 3-State Output Enable Time to Low Level and **Output Disable Time from Low Level** 



### **TEST CIRCUIT AND WAVEFORMS**

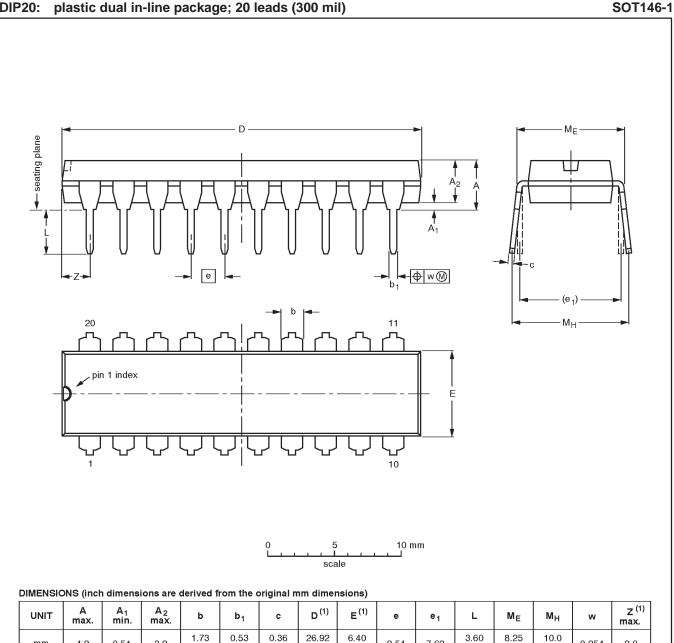


0.254

0.01

2.0

0.078



### **DIP20**: plastic dual in-line package; 20 leads (300 mil)

mm

inches

4.2

0.17

0.51

0.020

3.2

0.13

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

1.30 0.068

0.051

0.38

0.021

0.015

0.23

0.014

0.009

26.54

1.060

1.045

6.22

0.25

0.24

	OUTLINE VERSION	REFERENCES				EUROPEAN	ISSUE DATE
		IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
	SOT146-1			SC603			<del>-92-11-17</del> 95-05-24

2.54

0.10

7.62

0.30

3.05

0.14

0.12

7.80

0.32

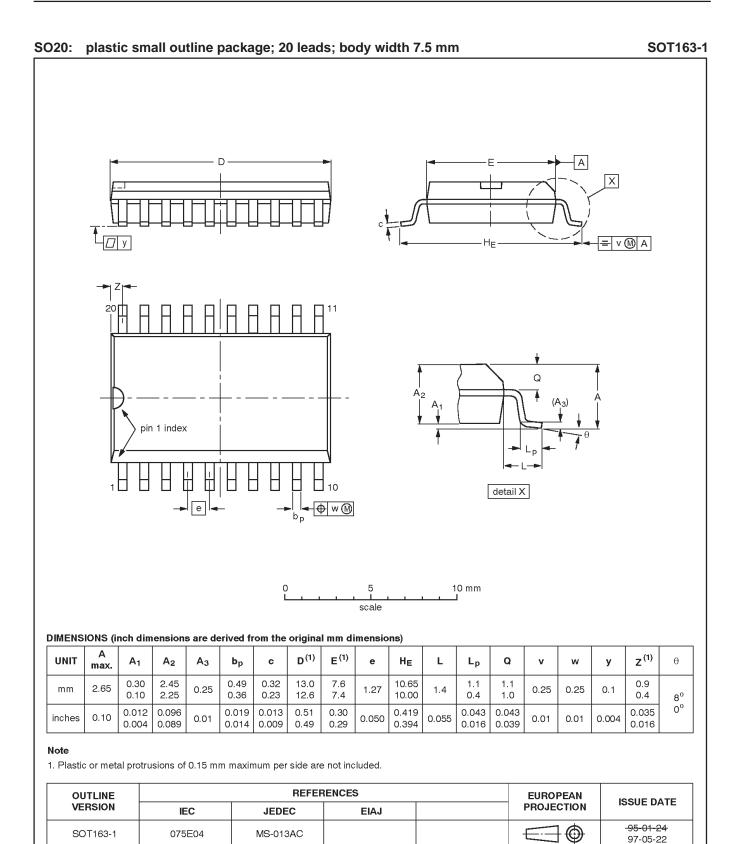
0.31

8.3

0.39

0.33

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NOTES

### Product specification

# 74F620, 74F623

### Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
		This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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